TRAN	ISMITTAL O	Docket No. SETI-0006							
In Re Application Of: Fareed et al.									
,	Serial No.		Examiner University	Group Art Unit					
10	0/659,183	September 10, 2003	Unknown	Unknown					
Title: HETEROSTRUCTURE SEMICONDUCTOR DEVICE									
•	Address to:  Commissioner for Patents  P.O. Box 1450  Alexandria, VA 22313-1450								
•		37	CFR 1.97(b)						
	The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.								
	37 CFR 1.97(c)  The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:								
•	☐ the statement specified in 37 CFR 1.97(e);								
		OR							
	☐ the fee se	t forth in 37 CFR 1.17(p).							

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT (Under 37 CFR 1.97(b) or 1.97(c) E									
In Re Application: Fareed et al.									
	,	Group Art Unit							
September 10, 2003	Unknown	Unknown							
HETEROSTRUCTURE SEMICONDUCTOR DEVICE									
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□ A check in the amount of is attached.  □ The Director is hereby authorized to charge and credit Deposit Account No. 500999  as described below. □ Charge the amount of □ Credit any overpayment. □ Charge any additional fee required. □ Certificate of Transmission by Facsimile*  □ Certificate of Transmission by Facsimile*  □ Certificate of Mailing by First Class Mai									
ame of Person Signing Certificate	Typed or Printed Name of Perso	n Mailing Certificate							
*This certificate may only be used if paying by deposit account.    Signature   Dated: October 30, 2003									
	Fareed et al.  Filing Date September 10, 2003  TURE SEMICONDUCTOR DEV  (Only complete if Applicant element of is attached and authorized to charge and cow).  The amount of is attached and is a series of the property of the complete in the	Fareed et al.  Filing Date September 10, 2003  TURE SEMICONDUCTOR DEVICE  Payment of Fee  (Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.1 and the complete of the co							

			Desired Number (Ontional)	Application Number		
-			Docket Number (Optional) SETI-0006	Application Number 10/659,183		
INFC	IRM!	ATION DISCLOSURE CITATION	Applicant(s)	10/02/,100		
AITA		(Use several sheets if necessary)	Fareed et al.			
	-	•	Filing Date	Group Art Unit		
			September 10, 2003	Unknown		
*EXAMINER INITIAL		OTHER DOCUMENTS (Including Author, Title	le, Date, Pertinent Pages, Etc.)			
MANA MANA		"Ferroelectric Semiconductors," V. M. Fridkin, Ru	issia (1976), p. 90 (pp. 64-65 in Englis	h version).		
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03	8	Charlottesville, VA, December 1997, pp. 377-380.	Tre Field Effect Hansiston, Wi. S. Sn	ur et al., Flocteuings of ISDNS-77,		
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TOWI O		"Optoelectronic GaN-Based Field Effect Transistor	rs," M. S. Shur et al., SPIE Vol. 2397,	рр. 294-303.		
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		"Current/Voltage Characteristic Collapse in AlGal	N/CaN Heterostructure Insulated Gat	e Field Effect Transistors at High		
	"Current/Voltage Characteristic Collapse in AlGaN/GaN Heterostructure Insulated Gate Field Effect Transistors at Hi Drain Bias," M. A. Khan et al., Electronic Letters, Vol. 30, No. 25, December 8, 1994, pp. 2175-2176.					
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EXAMINER		<b>!</b>	DATE CONSIDERED			
*EXAMINER: Init	tial if c	itation considered, whether or not citation is in conforma	nce with MPEP Section 609: Draw line the	rough citation if not in conformance and		

not considered. Include copy of this form with next communication to applicant.